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Docket: 500414.02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor:	Douglas D. Do and Jeff C. Johnson	<div>#12/RCE 7/26/01 VS</div>
Appln. No.:	09/629,022	
Filed:	July 31, 2000	
Title:	Method and Apparatus for Measuring Features of A Semiconductor Device	
		Examiner: K. Fernandez
		Group Art Unit: 2881

REQUEST FOR CONTINUED EXAMINATION (RCE)
UNDER 37 C.F.R. 1.114

Box RCE
Commissioner for Patents
Washington, D.C. 20231

I hereby certify that this document is being sent via First Class U. S. mail addressed to: Commissioner for Patents, Washington, D.C. 20231 on this 17 day of July, 2001.

Cynthia L. Salun
(Signature)

Sir:

Applicant requests continued examination, under 37 C.F.R. 1.114, of the above-identified application.

Submission Required Under 37 C.F.R. 1.114

The required submission was previously submitted. Please consider:

- i. ☒ the amendment/reply under 37 C.F.R. 1.116 previously filed on May 29, 2001.
- ii. ☐ the arguments in the Appeal Brief or Reply Brief previously filed on

Respectfully submitted,

Date: July 17, 2001

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